

WHAT IS CLAIMED IS:

1. A test apparatus for testing a plurality of devices under test, comprising:

5 a plurality of test modules, connected to either of the plurality of devices under test, for supplying a test signal to the connected device under test;

10 a plurality of control apparatuses for controlling said plurality of test modules, and for testing the plurality of devices under test in parallel; and

15 a connection setting section for setting topology of said plurality of control apparatuses and said plurality of test modules so that said plurality of control apparatuses connect with the plurality of devices under test respectively.

2. The test apparatus as claimed in claim 1, wherein the plurality of said control apparatuses control said plurality of test modules according to a test result of the plurality of devices under test respectively, and perform different test sequences to the plurality of devices under test in parallel.

3. The test apparatus as claimed in claim 1, wherein said connection setting section sets the topology for the test of the plurality of devices under test by said plurality of control apparatuses based on an instruction of one of said plurality of control apparatuses before the test of the plurality of devices under test by said plurality of control apparatuses.

4. The test apparatus as claimed in claim 1, wherein said connection setting section comprises:

30 a serial interface for transmitting a data packet received

from said test module to said control apparatus; and
an IDLE packet generating section for providing an IDLE
packet to fill an empty space in serial data transmitted by said
serial interface when said serial interface does not receive
5 the data packet from said test module.

5. The test apparatus as claimed in claim 1, wherein each
of the plurality of control apparatuses comprises:

10 a performance judging test executing section for ordering
to perform a performance judging test to the device under test
for judging performance of the device under test;

15 an operational specification determination section for
determining operational specifications of the device under test
based on result of the performance judging test;

an acceptability judging test executing section for
ordering to perform an acceptability judging test to the device
under test according to the operational specifications
determined by said operational specification determination
section; and

20 an acceptability judgment section for judging
acceptability of the device under test according to the
operational specifications determined by said operational
specification determination section based on the result of the
acceptability judging test.

25 6. A test apparatus for testing a plurality of devices under
test, comprising a plurality of control apparatuses for testing
the plurality of devices under test in parallel, wherein each
of said plurality of control apparatuses comprises:

30 a performance judging test executing section for ordering
to perform a performance judging test to the device under test

for judging performance of the device under test;

an operational specification determination section for determining operational specifications of the device under test based on result of the performance judging test;

5 an acceptability judging test executing section for ordering to perform an acceptability judging test to the device under test according to the operational specifications determined by said operational specification determination section; and

10 an acceptability judgment section for judging acceptability of the device under test according to the operational specifications determined by said operational specification determination section based on the result of the acceptability judging test.

15 7. The test apparatus as claimed in claim 6, wherein
 said performance judging test executing section orders
 to perform the performance judging test to the device under test
 for judging performance of memory of the device under test,

20 said operational specification determination section
 determines memory space, which is one of the operational
 specifications of the device under test, to be a memory space
 less than that of an operating part of the memory space when
 a part of the memory is not operating,

25 said acceptability judging test executing section orders
 to perform the acceptability judging test to the device under
 test, which is determined as a device including the memory space
 determined by said operational specification determination
 section, and

30 said acceptability judging section judges the
 acceptability of the device under test, which is determined as

a device including the memory space determined by said operational specification determination section.

8. A test method for testing a plurality of tested devices
5 in parallel with a plurality of control apparatuses respectively,
wherein each of the plurality of control apparatuses comprises
steps of:

ordering to perform a performance judging test to the device under test for judging performance of the device under test;

10 determining operational specifications of the device under test based on result of the performance judging test;

ordering to perform an acceptability judging test to the device under test according to the determined operational specifications; and

15 an acceptability judgment step section for judging acceptability of the device under test according to the determined operational specifications based on the result of the acceptability judging test.

20 9. A test method used for a test apparatus including a plurality of test modules, connected to either of the plurality of devices under test, for supplying a test signal to the connected device under test, and a plurality of control apparatuses for controlling the plurality of test modules, comprising steps of:

25 acquiring a connection switching setting data indicating topology of the plurality of control apparatuses and the plurality of test modules;

30 setting the topology of the plurality of control apparatuses and the plurality of test modules based on the connection switching setting data so that the plurality of control apparatuses connect with the plurality of devices under

test respectively; and

controlling by the plurality of control apparatus the plurality of test modules and testing the plurality of devices under test in parallel.